

SEMICONDUCTOR TM

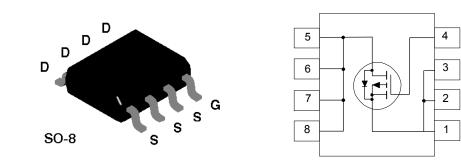
NDS8434 Single P-Channel Enhancement Mode Field Effect Transistor

General Description

transients are needed.

Features

- These P-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, high cell density, DMOS technology. This very high density process is especially tailored to minimize on-state resistance and provide superior switching performance. These devices are particularly suited for low voltage applications such as notebook computer power management and other battery powered circuits where
 - -6.5A, -20V. $R_{DS(ON)} = 0.035\Omega @ V_{GS} = -4.5V$ $R_{DS(ON)} = 0.05\Omega @ V_{GS} = -2.7V.$
 - High density cell design for extremely low R_{DS(ON)}.
 - High power and current handling capability in a widely used surface mount package.



Absolute Maximum Ratings T_A = 25°C unless otherwise noted

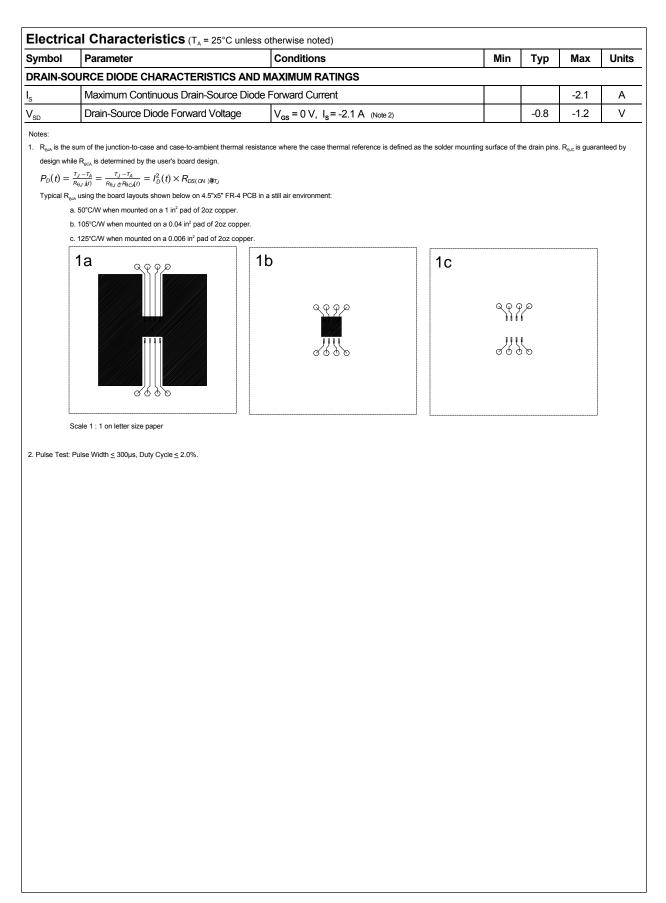
fast switching, low in-line power loss, and resistance to

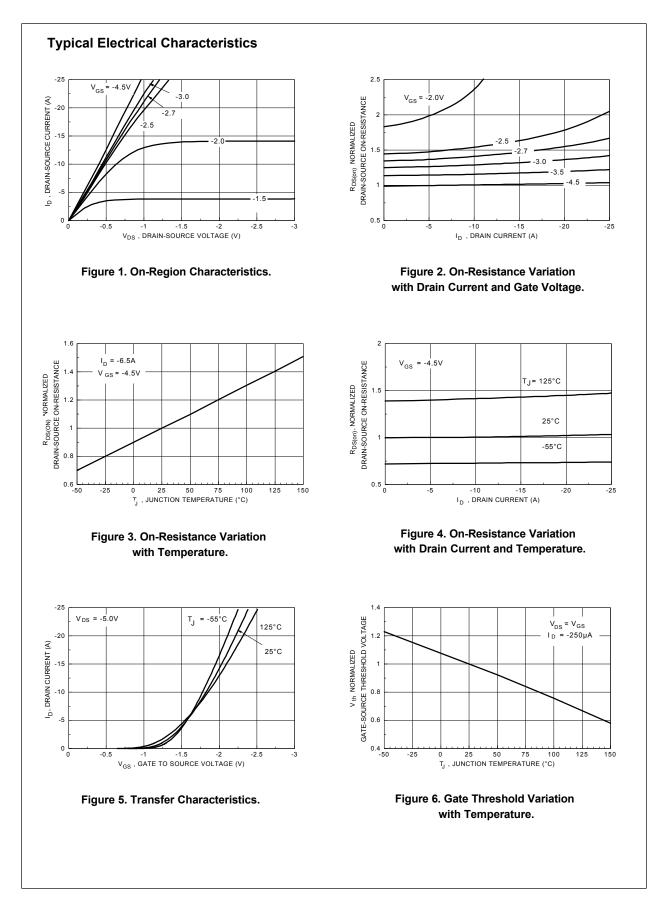
Symbol	Parameter		NDS8434	Units	
V _{DSS}	Drain-Source Voltage		-20	V	
V _{GSS}	Gate-Source Voltage		-8	V	
D	Drain Current - Continuous	(Note 1a)	-6.5	А	
	- Pulsed		-20		
P _D	Maximum Power Dissipation	(Note 1a)	2.5	W	
		(Note 1b)	1.2		
		(Note 1c)	1		
T_,T _{stg}	Operating and Storage Temperature Range	!	-55 to 150	C°	
THERMA	L CHARACTERISTICS				
R _{øja}	Thermal Resistance, Junction-to-Ambient	(Note 1a)	50	°C/W	
R _{øJC}	Thermal Resistance, Junction-to-Case	(Note 1)	25	°C/W	

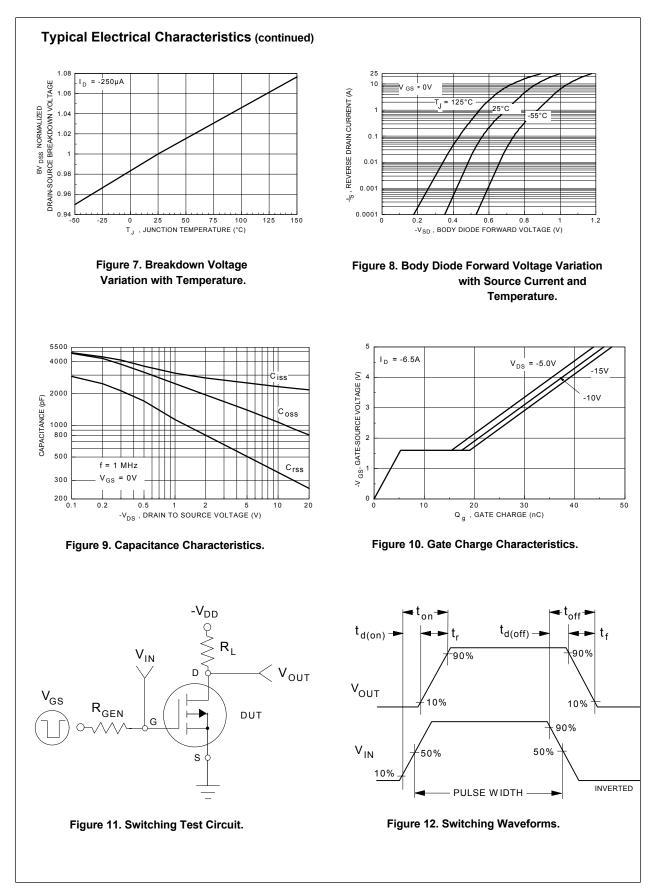
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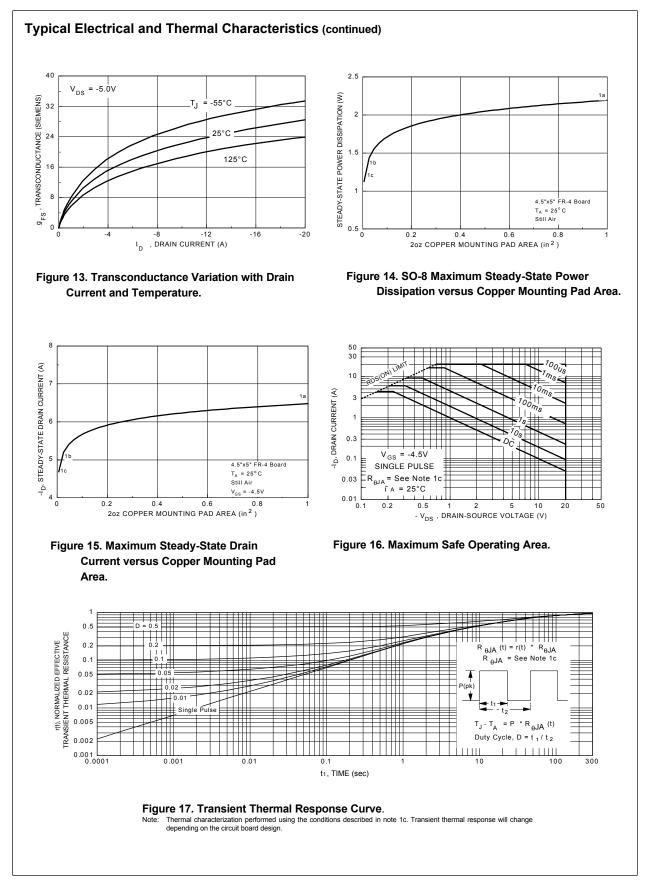
June 1996

Symbol	Parameter	Conditions		Min	Тур	Max	Units
OFF CHA	RACTERISTICS	·		•	•		
BV _{DSS}	Drain-Source Breakdown Voltage	V _{gs} = 0 V, I _p = -250 μA		-20			V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = -16 V, V _{GS} = 0 V				-1	μA
			T _J = 55°C			-10	μA
GSSF	Gate - Body Leakage, Forward	V _{GS} = 8 V, V _{DS} = 0 V	·			100	nA
GSSR	Gate - Body Leakage, Reverse	V _{GS} = -8 V, V _{DS} = 0 V				-100	nA
ON CHAR	ACTERISTICS (Note 2)						•
/ _{GS(th)}	Gate Threshold Voltage	$V_{\text{DS}} = V_{\text{GS}}, I_{\text{D}} = -250 \mu\text{A}$		-0.4	-0.7	-1	V
			T _J = 125°C	-0.3	-0.45	-0.8	1
R _{DS(ON)}	Static Drain-Source On-Resistance	$V_{gg} = -4.5 V, I_{p} = -6.5 A$			0.026	0.035	Ω
			T _J = 125°C		0.037	0.07]
		V _{gs} = -2.7 V, I _p = -5.5 A			0.036	0.05	1
I _{D(on)}	On-State Drain Current	$V_{GS} = -4.5 V, V_{DS} = -5 V$		-15			Α
		V_{GS} = -2.7 V, V_{DS} = -5 V		-10			
J _{FS}	Forward Transconductance	$V_{DS} = -10 \text{ V}, I_{D} = -6.5 \text{ A}$			18		S
DYNAMIC	CHARACTERISTICS			-			
2 _{iss}	Input Capacitance	$V_{DS} = -10 V, V_{GS} = 0 V,$ f = 1.0 MHz			2330		pF
C _{oss}	Output Capacitance				1070		pF
C _{rss}	Reverse Transfer Capacitance				360		pF
SWITCHIN	IG CHARACTERISTICS (Note 2)						
D(on)	Turn - On Delay Time	$V_{DD} = -6 \text{ V}, \text{ I}_{D} = -1 \text{ A},$ $V_{GEN} = -4.5 \text{ V}, \text{ R}_{GEN} = 6 \Omega$			20	40	ns
	Turn - On Rise Time				38	80	ns
D(off)	Turn - Off Delay Time				169	300	ns
	Turn - Off Fall Time				63	120	ns
ک ^و	Total Gate Charge	$V_{DS} = -5 V,$ $I_D = -6.5 A, V_{GS} = -4.5 V$			40	80	nC
ک _{gs}	Gate-Source Charge				5.3		nC
\mathbf{Q}_{gd}	Gate-Drain Charge				11		nC









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